

Title (en)  
Semiconductor integrated circuit

Title (de)  
Integrierte Halbleiterschaltung

Title (fr)  
Circuit intégré semi-conducteur

Publication  
**EP 0917068 A2 19990519 (EN)**

Application  
**EP 98121122 A 19981110**

Priority  
JP 33121397 A 19971114

Abstract (en)  
Micro-computer capable of independently testing an additional logic for user and a pre-existing micro-computer portion in a shipment test of the micro-computer having the enclosed additional logic for user. A logic dedicated to connection is directly coupled to an internal bus of the micro-computer and is provided between the additional logic for user and the micro-computer . For testing the additional logic for user, a bus/port changeover terminal of the micro-computer and a read/write signal are used to effect readout/writing. Also, a bus inspection register is provided in the logic dedicated to connection. For testing the micro-computer, an output of the inspection register is read out to a bus of the logic dedicated to connection to inspect the bus. <IMAGE>

IPC 1-7  
**G06F 15/78**; **G06F 13/20**; **G06F 11/273**

IPC 8 full level  
**G01R 31/28** (2006.01); **G06F 11/22** (2006.01); **G06F 11/267** (2006.01); **G06F 13/24** (2006.01); **G06F 15/78** (2006.01); **H01L 21/822** (2006.01); **H01L 27/04** (2006.01)

CPC (source: EP KR US)  
**G06F 11/2236** (2013.01 - EP KR US); **G06F 11/25** (2013.01 - KR); **G06F 13/24** (2013.01 - EP KR US); **G06F 15/7832** (2013.01 - EP KR US)

Designated contracting state (EPC)  
DE FR GB

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